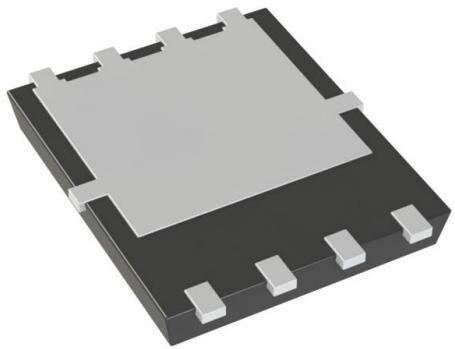


# AON6444L Datasheet

[www.digi-electronics.com](http://www.digi-electronics.com)



DiGi Electronics Part Number	AON6444L-DG
Manufacturer	<a href="#">Alpha &amp; Omega Semiconductor Inc.</a>
Manufacturer Product Number	AON6444L
Description	MOSFET N-CH 60V 8DFN
Detailed Description	81A (T <sub>c</sub> ) Surface Mount 8-DFN (5x6)

<https://www.DiGi-Electronics.com>



Tel: +00 852-30501935

RFQ Email: [Info@DiGi-Electronics.com](mailto:Info@DiGi-Electronics.com)

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## Purchase and inquiry

Manufacturer Product Number:	Manufacturer:
AON6444L	Alpha & Omega Semiconductor Inc.
Series:	Product Status:
SDMOS™	Obsolete
Current - Continuous Drain (Id) @ 25°C:	Mounting Type:
81A (T <sub>c</sub> )	Surface Mount
Supplier Device Package:	Package / Case:
8-DFN (5x6)	8-PowerSMD, Flat Leads
Base Product Number:	
AON644	

## Environmental & Export classification

Moisture Sensitivity Level (MSL):	REACH Status:
1 (Unlimited)	REACH Unaffected
ECCN:	HTSUS:
OBSOLETE	0000.00.0000



# AON6444L

**60V N-Channel MOSFET**  
**SDMOS™**

## General Description

The AON6444L is fabricated with SDMOS™ trench technology that combines excellent  $R_{DS(ON)}$  with low gate charge. The result is outstanding efficiency with controlled switching behavior. This universal technology is well suited for PWM, load switching and general purpose applications.

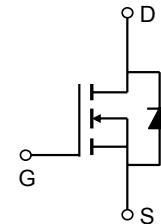
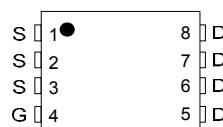
## Product Summary

$V_{DS}$	60V
$I_D$ (at $V_{GS}=10V$ )	81A
$R_{DS(ON)}$ (at $V_{GS}=10V$ )	< 6.5mΩ
$R_{DS(ON)}$ (at $V_{GS} = 4.5V$ )	< 8mΩ

100% UIS Tested  
100%  $R_g$  Tested



Top View



DFN5X6

## Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	60	V
Gate-Source Voltage	$V_{GS}$	±20	V
Continuous Drain Current	$I_D$	81	A
$T_C=100^\circ C$		51	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	170	
Continuous Drain Current	$I_{DSM}$	14	A
$T_A=70^\circ C$		11	
Avalanche Current <sup>C</sup>	$I_{AR}$	58	A
Repetitive avalanche energy $L=0.1mH$ <sup>C</sup>	$E_{AR}$	168	mJ
Power Dissipation <sup>B</sup>	$P_D$	83	W
$T_C=100^\circ C$		33	
Power Dissipation <sup>A</sup>	$P_{DSM}$	2.3	W
$T_A=70^\circ C$		1.4	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 150	°C

## Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	$R_{0JA}$	14	17	°C/W
Maximum Junction-to-Ambient <sup>A,D</sup>		40	55	°C/W
Maximum Junction-to-Case	$R_{0JC}$	1	1.5	°C/W

**Electrical Characteristics (T<sub>J</sub>=25°C unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	I <sub>D</sub> =250μA, V <sub>GS</sub> =0V	60			V
I <sub>DS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =60V, V <sub>GS</sub> =0V T <sub>J</sub> =55°C			100 500	μA
I <sub>GSS</sub>	Gate-Body leakage current	V <sub>DS</sub> =0V, V <sub>GS</sub> =±20V			100	nA
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250μA	1.5	2	2.5	V
I <sub>D(ON)</sub>	On state drain current	V <sub>GS</sub> =10V, V <sub>DS</sub> =5V	170			A
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance	V <sub>GS</sub> =10V, I <sub>D</sub> =20A T <sub>J</sub> =125°C		5.4 9.6	6.5 11.5	mΩ
		V <sub>GS</sub> =4.5V, I <sub>D</sub> =20A		6.4	8	mΩ
g <sub>FS</sub>	Forward Transconductance	V <sub>DS</sub> =5V, I <sub>D</sub> =20A		75		S
V <sub>SD</sub>	Diode Forward Voltage	I <sub>S</sub> =1A, V <sub>GS</sub> =0V		0.7	1	V
I <sub>S</sub>	Maximum Body-Diode Continuous Current			81		A
<b>DYNAMIC PARAMETERS</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>GS</sub> =0V, V <sub>DS</sub> =30V, f=1MHz	3800	4800	5800	pF
C <sub>oss</sub>	Output Capacitance		330	470	610	pF
C <sub>rss</sub>	Reverse Transfer Capacitance		110	190	270	pF
R <sub>g</sub>	Gate resistance	V <sub>GS</sub> =0V, V <sub>DS</sub> =0V, f=1MHz	0.5	1	1.5	Ω
<b>SWITCHING PARAMETERS</b>						
Q <sub>g</sub> (10V)	Total Gate Charge	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, I <sub>D</sub> =20A	64	80	96	nC
Q <sub>g</sub> (4.5V)	Total Gate Charge		32	40	48	nC
Q <sub>gs</sub>	Gate Source Charge		12	15	18	nC
Q <sub>gd</sub>	Gate Drain Charge		8	14	20	nC
t <sub>D(on)</sub>	Turn-On Delay Time	V <sub>GS</sub> =10V, V <sub>DS</sub> =30V, R <sub>L</sub> =1.5Ω, R <sub>GEN</sub> =3Ω		13.5		ns
t <sub>r</sub>	Turn-On Rise Time			4.2		ns
t <sub>D(off)</sub>	Turn-Off Delay Time			51		ns
t <sub>f</sub>	Turn-Off Fall Time			7		ns
t <sub>rr</sub>	Body Diode Reverse Recovery Time	I <sub>F</sub> =20A, dI/dt=500A/μs	14	18	22	ns
Q <sub>rr</sub>	Body Diode Reverse Recovery Charge	I <sub>F</sub> =20A, dI/dt=500A/μs	43	54	65	nC

A. The value of R<sub>θJA</sub> is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C. The Power dissipation P<sub>DSM</sub> is based on R<sub>θJA</sub> and the maximum allowed junction temperature of 150°C. The value in any given application depends on the user's specific board design, and the maximum temperature of 150°C may be used if the PCB allows it.

B. The power dissipation P<sub>D</sub> is based on T<sub>J(MAX)</sub>=150°C, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Repetitive rating, pulse width limited by junction temperature T<sub>J(MAX)</sub>=150°C. Ratings are based on low frequency and duty cycles to keep initial T<sub>J</sub>=25°C.

D. The R<sub>θJA</sub> is the sum of the thermal impedance from junction to case R<sub>θJC</sub> and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using <300μs pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of T<sub>J(MAX)</sub>=150°C. The SOA curve provides a single pulse rating.

G. These tests are performed with the device mounted on 1 in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with T<sub>A</sub>=25°C.

Rev 0: January 2009

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AON6444L

## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

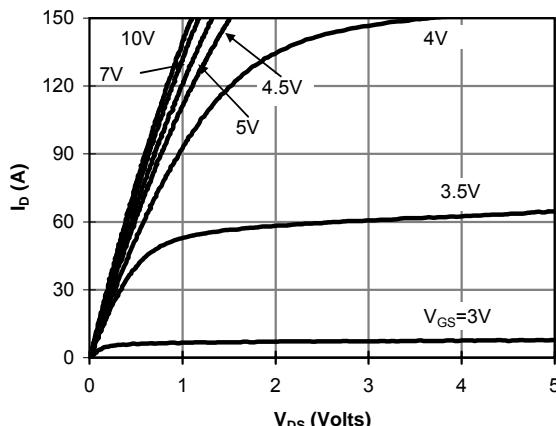


Fig 1: On-Region Characteristics (Note E)

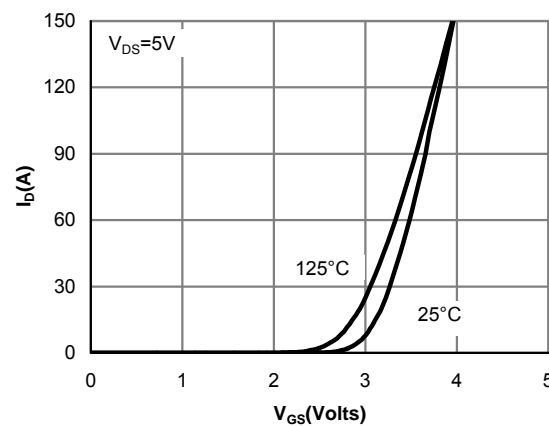


Figure 2: Transfer Characteristics (Note E)

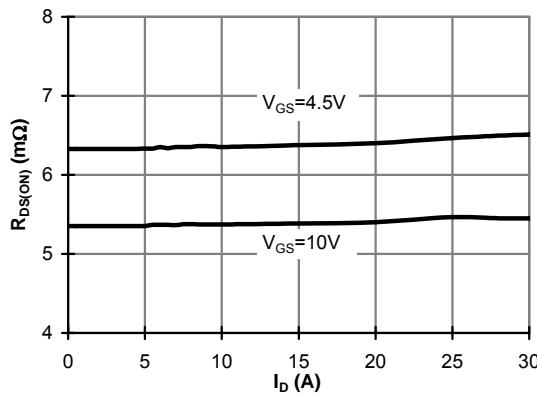


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

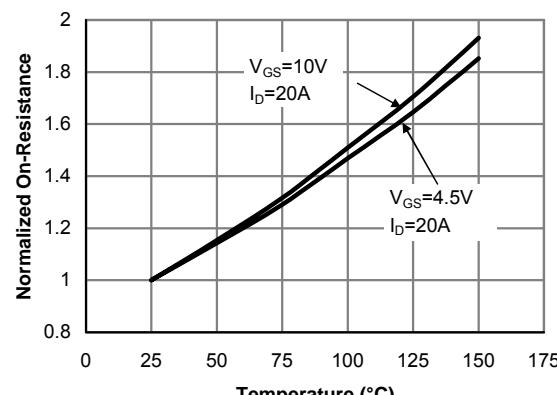


Figure 4: On-Resistance vs. Junction Temperature (Note E)

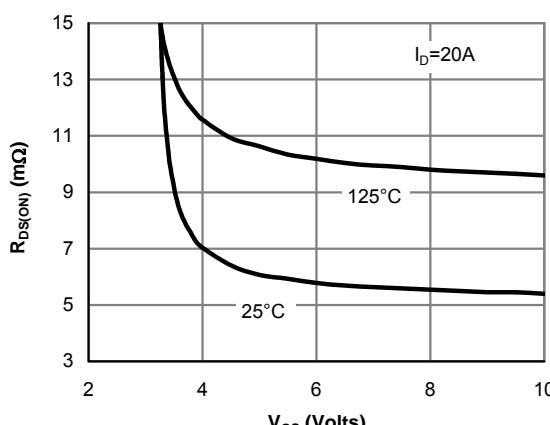


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

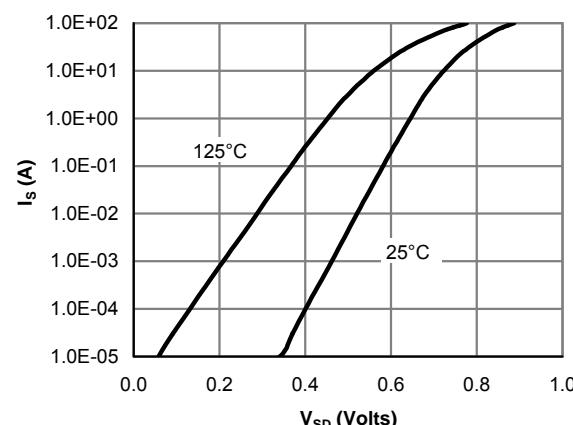


Figure 6: Body-Diode Characteristics (Note E)



## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

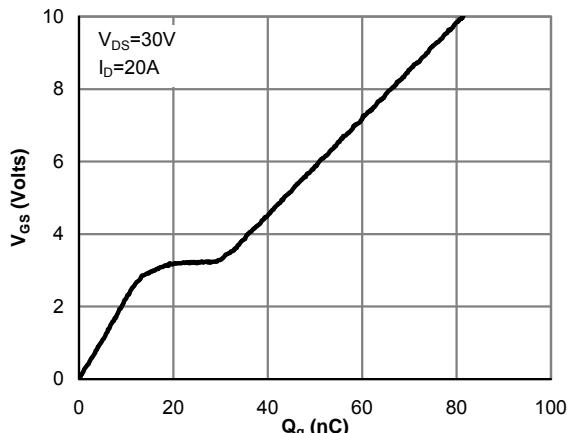


Figure 7: Gate-Charge Characteristics

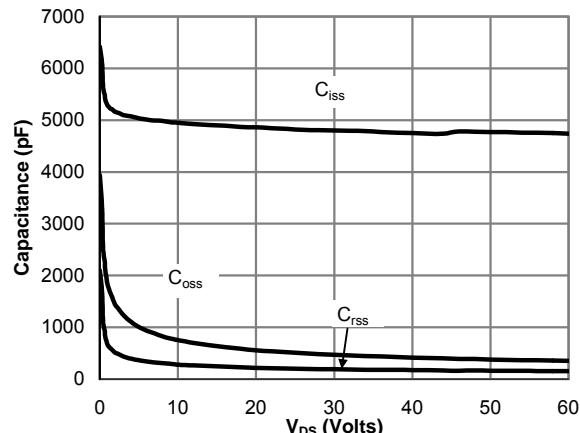


Figure 8: Capacitance Characteristics

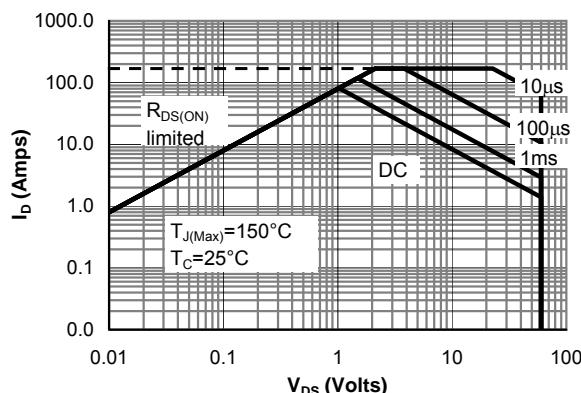


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

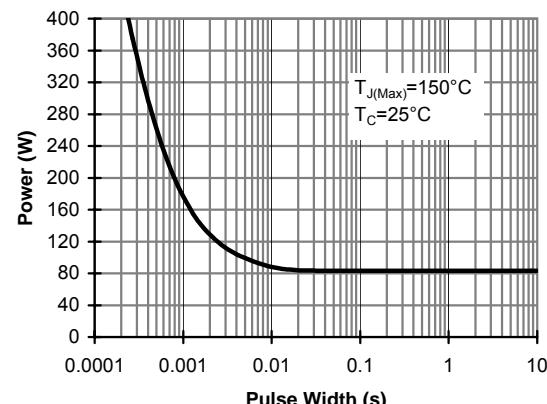


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

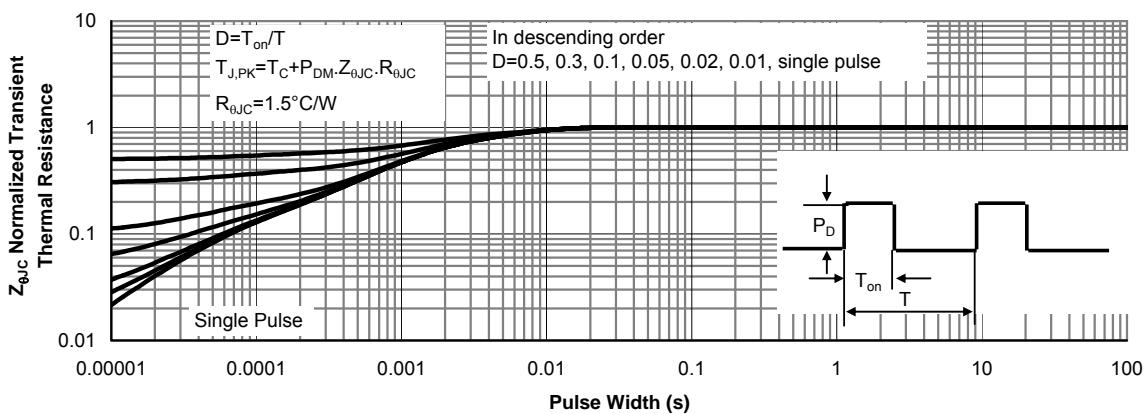


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



## TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

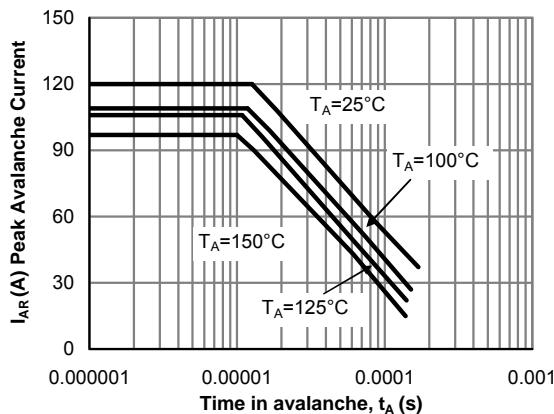


Figure 12: Single Pulse Avalanche capability (Note C)

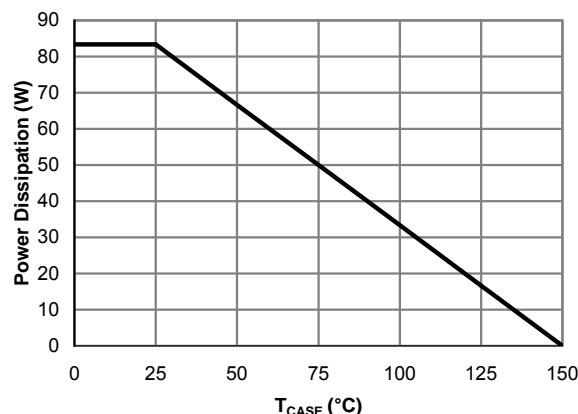


Figure 13: Power De-rating (Note F)

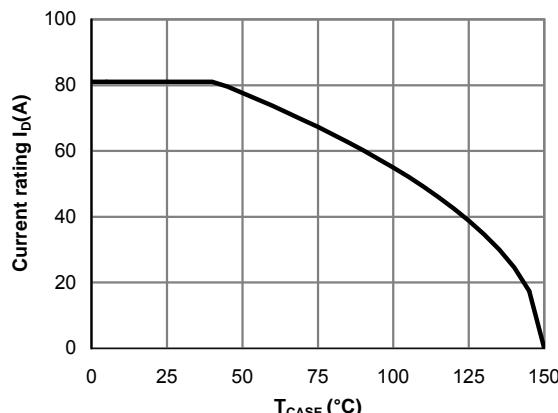


Figure 14: Current De-rating (Note F)

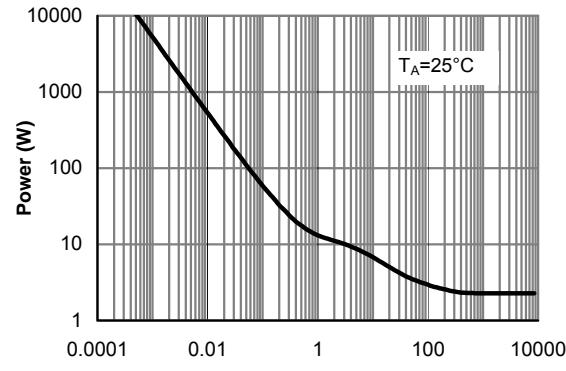


Figure 15: Single Pulse Power Rating Junction-to-Ambient (Note G)

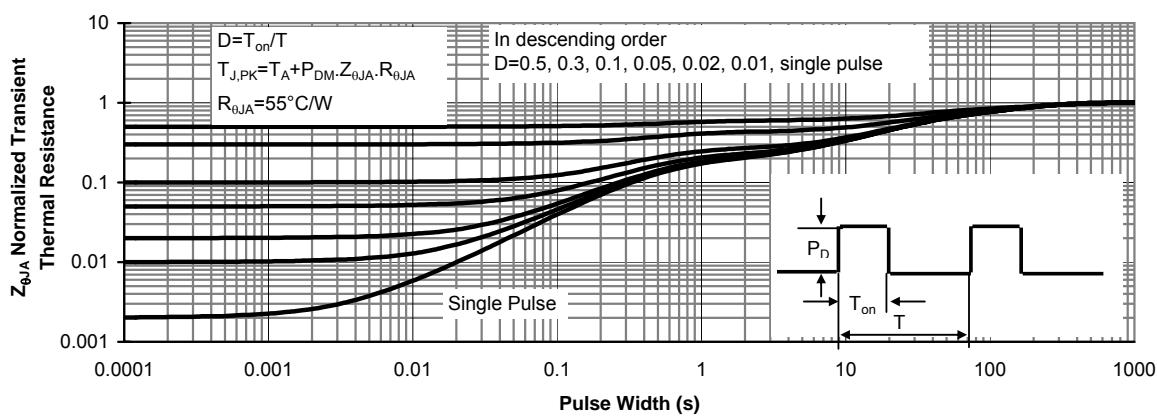


Figure 16: Normalized Maximum Transient Thermal Impedance (Note G)

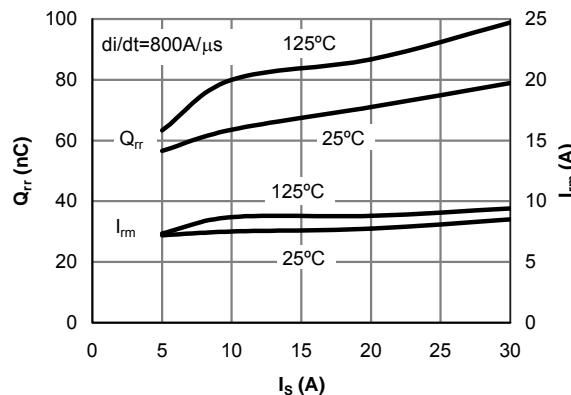
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 17: Diode Reverse Recovery Charge and Peak Current vs. Conduction Current

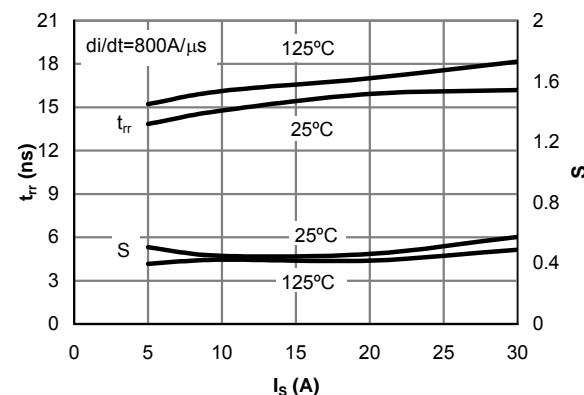


Figure 18: Diode Reverse Recovery Time and Softness Factor vs. Conduction Current

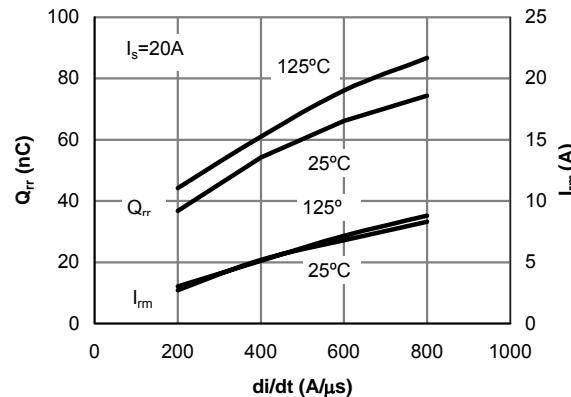


Figure 19: Diode Reverse Recovery Charge and Peak Current vs. di/dt

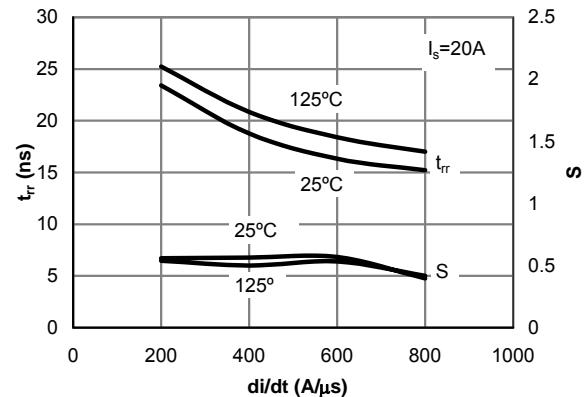
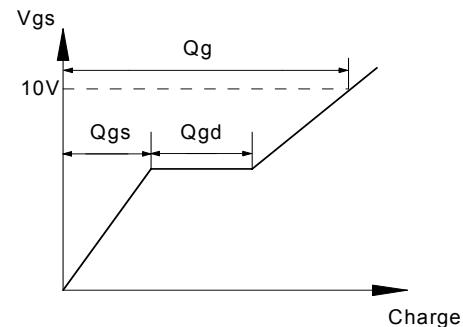
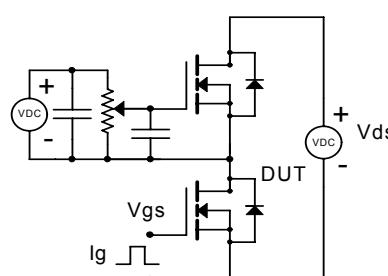
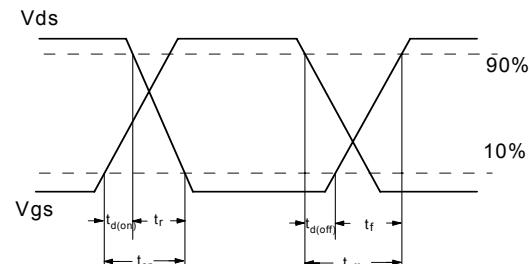
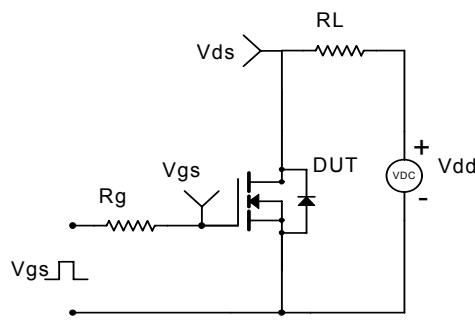
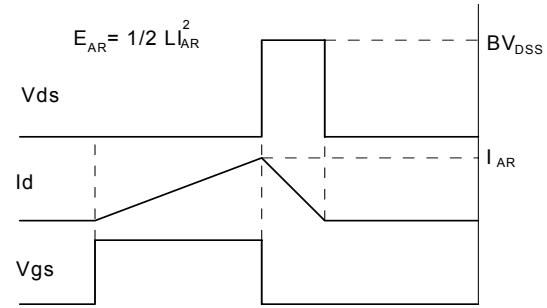
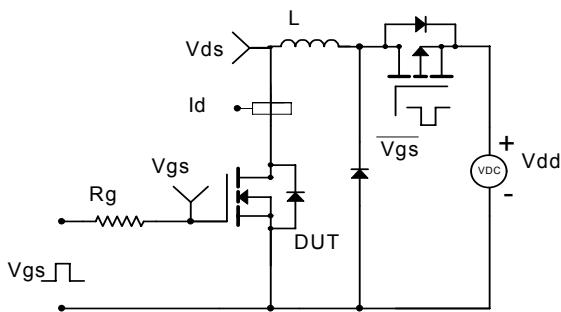
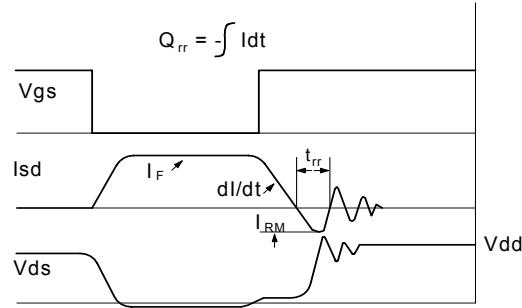
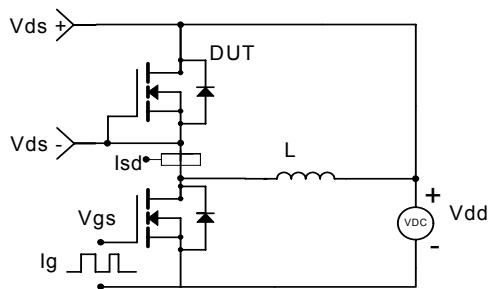


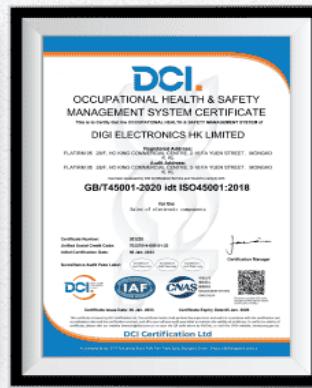
Figure 20: Diode Reverse Recovery Time and Softness Factor vs. di/dt

**Gate Charge Test Circuit & Waveform****Resistive Switching Test Circuit & Waveforms****Unclamped Inductive Switching (UIS) Test Circuit & Waveforms****Diode Recovery Test Circuit & Waveforms**

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